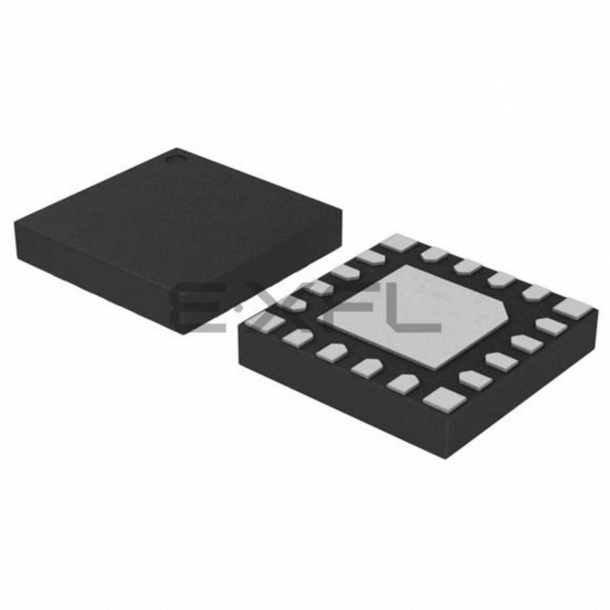

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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	25MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	16
Program Memory Size	2KB (2K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	256 x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 15x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	20-WFQFN Exposed Pad
Supplier Device Package	20-QFN (3x3)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb10f2a-a-qfn20r

3. System Overview

3.1 Introduction

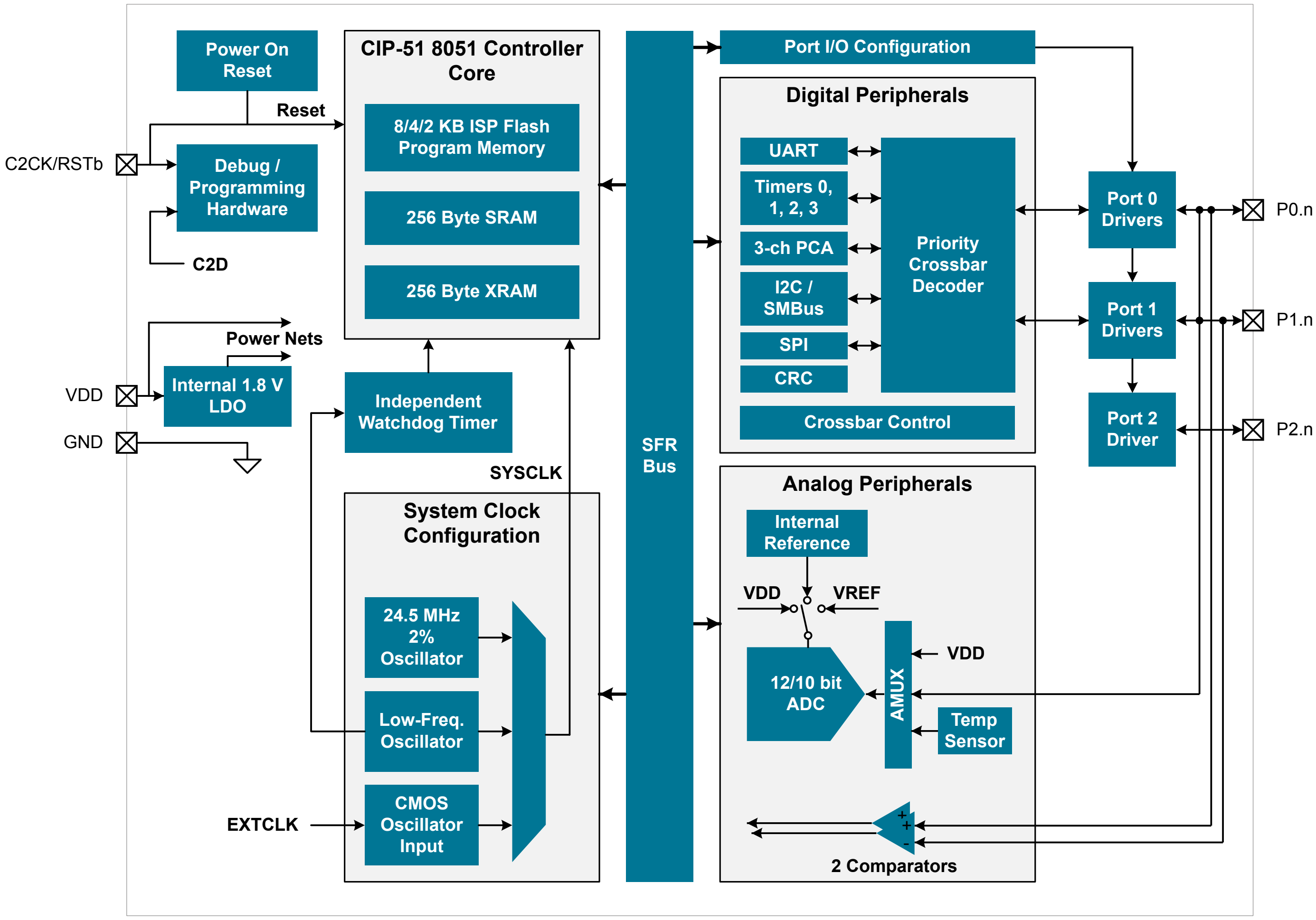


Figure 3.1. Detailed EFM8BB1 Block Diagram

This section describes the EFM8BB1 family at a high level. For more information on each module including register definitions, see the EFM8BB1 Reference Manual.

3.5 Counters/Timers and PWM

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- 16-bit time base
- Programmable clock divisor and clock source selection
- Up to three independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (center or edge-aligned operation)
- Output polarity control
- Frequency output mode
- Capture on rising, falling or any edge
- Compare function for arbitrary waveform generation
- Software timer (internal compare) mode
- Can accept hardware “kill” signal from comparator 0

Timers (Timer 0, Timer 1, Timer 2, and Timer 3)

Several counter/timers are included in the device: two are 16-bit counter/timers compatible with those found in the standard 8051, and the rest are 16-bit auto-reload timers for timing peripherals or for general purpose use. These timers can be used to measure time intervals, count external events and generate periodic interrupt requests. Timer 0 and Timer 1 are nearly identical and have four primary modes of operation. The other timers offer both 16-bit and split 8-bit timer functionality with auto-reload and capture capabilities.

Timer 0 and Timer 1 include the following features:

- Standard 8051 timers, supporting backwards-compatibility with firmware and hardware.
- Clock sources include SYSCLK, SYSCLK divided by 12, 4, or 48, the External Clock divided by 8, or an external pin.
- 8-bit auto-reload counter/timer mode
- 13-bit counter/timer mode
- 16-bit counter/timer mode
- Dual 8-bit counter/timer mode (Timer 0)

Timer 2 and Timer 3 are 16-bit timers including the following features:

- Clock sources include SYSCLK, SYSCLK divided by 12, or the External Clock divided by 8.
- 16-bit auto-reload timer mode
- Dual 8-bit auto-reload timer mode
- External pin capture (Timer 2)
- LFOSC0 capture (Timer 3)

Watchdog Timer (WDT0)

The device includes a programmable watchdog timer (WDT) running off the low-frequency oscillator. A WDT overflow forces the MCU into the reset state. To prevent the reset, the WDT must be restarted by application software before overflow. If the system experiences a software or hardware malfunction preventing the software from restarting the WDT, the WDT overflows and causes a reset. Following a reset, the WDT is automatically enabled and running with the default maximum time interval. If needed, the WDT can be disabled by system software or locked on to prevent accidental disabling. Once locked, the WDT cannot be disabled until the next system reset. The state of the RST pin is unaffected by this reset.

The Watchdog Timer has the following features:

- Programmable timeout interval
- Runs from the low-frequency oscillator
- Lock-out feature to prevent any modification until a system reset

3.10 Bootloader

All devices come pre-programmed with a UART bootloader. This bootloader resides in the code security page, which is the last last page of code flash; it can be erased if it is not needed.

The byte before the Lock Byte is the Bootloader Signature Byte. Setting this byte to a value of 0xA5 indicates the presence of the bootloader in the system. Any other value in this location indicates that the bootloader is not present in flash.

When a bootloader is present, the device will jump to the bootloader vector after any reset, allowing the bootloader to run. The bootloader then determines if the device should stay in bootload mode or jump to the reset vector located at 0x0000. When the bootloader is not present, the device will jump to the reset vector of 0x0000 after any reset.

More information about the bootloader protocol and usage can be found in *AN945: EFM8 Factory Bootloader User Guide*. Application notes can be found on the Silicon Labs website (www.silabs.com/8bit-appnotes) or within Simplicity Studio by using the [**Application Notes**] tile.

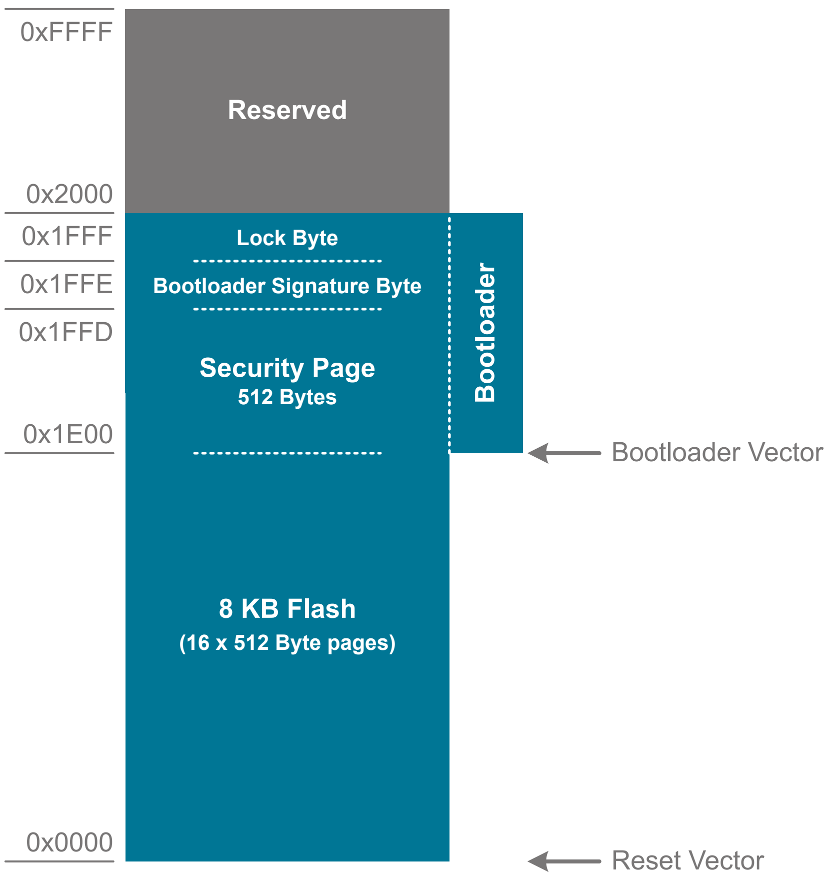


Figure 3.2. Flash Memory Map with Bootloader—8 KB Devices

Table 3.2. Summary of Pins for Bootloader Communication

Bootloader	Pins for Bootload Communication
UART	TX – P0.4
	RX – P0.5

4. Electrical Specifications

4.1 Electrical Characteristics

All electrical parameters in all tables are specified under the conditions listed in Table 4.1 Recommended Operating Conditions on page 12, unless stated otherwise.

4.1.1 Recommended Operating Conditions

Table 4.1. Recommended Operating Conditions

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Operating Supply Voltage on VDD	V_{DD}		2.2	—	3.6	V
System Clock Frequency	f_{SYSCLK}		0	—	25	MHz
Operating Ambient Temperature	T_A	G-grade devices	–40	—	85	°C
		I-grade or A-grade devices	-40	—	125	°C

Note:
1. All voltages with respect to GND
2. GPIO levels are undefined whenever VDD is less than 1 V.

4.1.2 Power Consumption

Table 4.2. Power Consumption

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Digital Core Supply Current (G-grade devices, -40 °C to +85 °C)						
Normal Mode—Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	4.45	4.85	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	915	1150	μA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	250	290	μA
		F_{SYSCLK} = 80 kHz[3]	—	250	380	μA
Idle Mode—Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	2.05	2.3	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	550	700	μA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	125	130	μA
		F_{SYSCLK} = 80 kHz[3]	—	125	200	μA
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}	T_A = 25 °C	—	105	120	μA
		T_A = -40 to +85 °C	—	105	170	μA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	—	μA
Digital Core Supply Current (I-grade or A-grade devices, -40 °C to +125 °C)						
Normal Mode—Full speed with code executing from flash	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	4.45	5.25	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	915	1600	μA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	250	290	μA
		F_{SYSCLK} = 80 kHz[3]	—	250	725	μA
Idle Mode—Core halted with peripherals running	I_{DD}	F_{SYSCLK} = 24.5 MHz[2]	—	2.05	2.6	mA
		F_{SYSCLK} = 1.53 MHz[2]	—	550	1000	μA
		F_{SYSCLK} = 80 kHz[3] , T_A = 25 °C	—	125	130	μA
		F_{SYSCLK} = 80 kHz[3]	—	125	550	μA
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}	T_A = 25 °C	—	105	120	μA
		T_A = -40 to +125 °C	—	105	270	μA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	—	μA
Analog Peripheral Supply Currents (-40 °C to +125 °C)						
High-Frequency Oscillator	I_{HFOSC}	Operating at 24.5 MHz, T_A = 25 °C	—	155	—	μA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	3.5	—	μA

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit

Note:
1. Currents are additive. For example, where I_{DD} is specified and the mode is not mutually exclusive, enabling the functions increases supply current by the specified amount.
2. Includes supply current from internal regulator, supply monitor, and High Frequency Oscillator.
3. Includes supply current from internal regulator, supply monitor, and Low Frequency Oscillator.
4. ADC0 always-on power excludes internal reference supply current.
5. The internal reference is enabled as-needed when operating the ADC in burst mode to save power.

4.1.3 Reset and Supply Monitor

Table 4.3. Reset and Supply Monitor

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
V_{DD} Supply Monitor Threshold	V_{VDDM}		1.85[1]	1.95	2.1	V
Power-On Reset (POR) Threshold	V_{POR}	Rising Voltage on V_{DD}	—	1.4	—	V
		Falling Voltage on V_{DD}	0.75	—	1.36	V
V_{DD} Ramp Time	t_{RMP}	Time to $V_{DD} \geq 2.2$ V	10	—	—	µs
Reset Delay from POR	t_{POR}	Relative to $V_{DD} \geq V_{POR}$	3	10	31	ms
Reset Delay from non-POR source	t_{RST}	Time between release of reset source and code execution	—	39	—	µs
RST Low Time to Generate Reset	t_{RSTL}		15	—	—	µs
Missing Clock Detector Response Time (final rising edge to reset)	t_{MCD}	$F_{SYSCLK} > 1$ MHz	—	0.625	1.2	ms
Missing Clock Detector Trigger Frequency	F_{MCD}		—	7.5	13.5	kHz
V_{DD} Supply Monitor Turn-On Time	t_{MON}		—	2	—	µs

Note:
1. MCU core, digital logic, flash memory, and RAM operation is guaranteed down to the minimum VDD Supply Monitor Threshold.

4.1.6 External Clock Input

Table 4.6. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	25	MHz
External Input CMOS Clock High Time	t_{CMOSH}		18	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		18	—	—	ns

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Slope Error	E_M	12 Bit Mode	—	±0.02	±0.1	%
		10 Bit Mode	—	±0.06	±0.24	%
Dynamic Performance 10 kHz Sine Wave Input 1dB below full scale, Max throughput, using AGND pin						
Signal-to-Noise	SNR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Signal-to-Noise Plus Distortion	SNDR	12 Bit Mode	61	66	—	dB
		10 Bit Mode	53	60	—	dB
Total Harmonic Distortion (Up to 5th Harmonic)	THD	12 Bit Mode	—	71	—	dB
		10 Bit Mode	—	70	—	dB
Spurious-Free Dynamic Range	SFDR	12 Bit Mode	—	–79	—	dB
		10 Bit Mode	—	–74	—	dB

Note:

1. Absolute input pin voltage is limited by the V_{DD} supply.

4.1.8 Voltage Reference

Table 4.8. Voltage Reference

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Internal Fast Settling Reference						
Output Voltage (Full Temperature and Supply Range)	V_{REFFS}	1.65 V Setting	1.62	1.65	1.68	V
		2.4 V Setting, V_{DD} ≥ 2.6 V	2.35	2.4	2.45	V
Temperature Coefficient	TC_{REFFS}		—	50	—	ppm/°C
Turn-on Time	t_{REFFS}		—	—	1.5	µs
Power Supply Rejection	$PSRR_{REFFS}$		—	400	—	ppm/V
External Reference						
Input Current	I_{EXTREF}	Sample Rate = 800 ksps; VREF = 3.0 V	—	5	—	µA

4.1.11 Comparators

Table 4.11. Comparators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Response Time, CPMD = 00 (Highest Speed)	t_{RESP0}	+100 mV Differential	—	100	—	ns
		–100 mV Differential	—	150	—	ns
Response Time, CPMD = 11 (Lowest Power)	t_{RESP3}	+100 mV Differential	—	1.5	—	µs
		–100 mV Differential	—	3.5	—	µs
Positive Hysterisis Mode 0 (CPMD = 00)	HYS_{CP+}	CPHYP = 00	—	0.4	—	mV
		CPHYP = 01	—	8	—	mV
		CPHYP = 10	—	16	—	mV
		CPHYP = 11	—	32	—	mV
Negative Hysterisis Mode 0 (CPMD = 00)	HYS_{CP-}	CPHYN = 00	—	-0.4	—	mV
		CPHYN = 01	—	–8	—	mV
		CPHYN = 10	—	–16	—	mV
		CPHYN = 11	—	–32	—	mV
Positive Hysterisis Mode 1 (CPMD = 01)	HYS_{CP+}	CPHYP = 00	—	0.5	—	mV
		CPHYP = 01	—	6	—	mV
		CPHYP = 10	—	12	—	mV
		CPHYP = 11	—	24	—	mV
Negative Hysterisis Mode 1 (CPMD = 01)	HYS_{CP-}	CPHYN = 00	—	-0.5	—	mV
		CPHYN = 01	—	–6	—	mV
		CPHYN = 10	—	–12	—	mV
		CPHYN = 11	—	–24	—	mV
Positive Hysterisis Mode 2 (CPMD = 10)	HYS_{CP+}	CPHYP = 00	—	0.7	—	mV
		CPHYP = 01	—	4.5	—	mV
		CPHYP = 10	—	9	—	mV
		CPHYP = 11	—	18	—	mV
Negative Hysterisis Mode 2 (CPMD = 10)	HYS_{CP-}	CPHYN = 00	—	-0.6	—	mV
		CPHYN = 01	—	–4.5	—	mV
		CPHYN = 10	—	–9	—	mV
		CPHYN = 11	—	–18	—	mV
Positive Hysteresis Mode 3 (CPMD = 11)	HYS_{CP+}	CPHYP = 00	—	1.5	—	mV
		CPHYP = 01	—	4	—	mV
		CPHYP = 10	—	8	—	mV
		CPHYP = 11	—	16	—	mV

4.1.12 Port I/O

Table 4.12. Port I/O

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Output High Voltage (Low Drive)[1]	V_{OH}	I_{OH} = –1 mA	V_{DD} – 0.7	—	—	V
Output High Voltage (High Drive)[1]	V_{OH}	I_{OH} = –3 mA	V_{DD} – 0.7	—	—	V
Output Low Voltage (Low Drive)[1]	V_{OL}	I_{OL} = 1.4 mA	—	—	0.6	V
Output Low Voltage (High Drive)[1]	V_{OL}	I_{OL} = 8.5 mA	—	—	0.6	V
Output Low Voltage (High Drive)[1]	V_{OL}	I_{OL} = 10 mA -10 °C ≤ T_A ≤ 60 °C V_{DD} = 3.0 V Guaranteed by characterization	—	0.25	0.33	V
Output Low Voltage (High Drive)[1]	V_{OL}	I_{OL} = 10 mA -10 °C ≤ T_A ≤ 60 °C V_{DD} = 3.6 V Guaranteed by characterization	—	0.23	0.31	V
Input High Voltage	V_{IH}		V_{DD} – 0.6	—	—	V
Input Low Voltage	V_{IL}		—	—	0.6	V
Pin Capacitance	C_{IO}		—	7	—	pF
Weak Pull-Up Current (V_{IN} = 0 V)	I_{PU}	V_{DD} = 3.6	–30	–20	–10	µA
Input Leakage (Pullups off or Analog)	I_{LK}	GND < V_{IN} < V_{DD}	–1.1	—	1.1	µA
Input Leakage Current with V_{IN} above V_{DD}	I_{LK}	V_{DD} < V_{IN} < V_{DD}+2.0 V	0	5	150	µA

Note:

1. See Figure 4.6 Typical V_{OH} Curves on page 30 and Figure 4.7 Typical V_{OL} Curves on page 30 for more information.

4.1.13 SMBus

Table 4.13. SMBus Peripheral Timing Performance (Master Mode)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Standard Mode (100 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	70[2]	kHz
SMBus Operating Frequency	f_{SMB}		40[1]	—	70[2]	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		9.4	—	—	µs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		4.7	—	—	µs
Repeated START Condition Setup Time	$t_{SU:STA}$		9.4	—	—	µs
STOP Condition Setup Time	$t_{SU:STO}$		9.4	—	—	µs
Data Hold Time	$t_{HD:DAT}$		489[3]	—	—	ns
Data Setup Time	$t_{SU:DAT}$		448[3]	—	—	ns
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		4.7	—	—	µs
Clock High Period	t_{HIGH}		9.4	—	50[4]	µs
Fast Mode (400 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	255[2]	kHz
SMBus Operating Frequency	f_{SMB}		40[1]	—	255[2]	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		2.6	—	—	µs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		1.3	—	—	µs
Repeated START Condition Setup Time	$t_{SU:STA}$		2.6	—	—	µs
STOP Condition Setup Time	$t_{SU:STO}$		2.6	—	—	µs
Data Hold Time	$t_{HD:DAT}$		489[3]	—	—	ns
Data Setup Time	$t_{SU:DAT}$		448[3]	—	—	ns
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		1.3	—	—	µs
Clock High Period	t_{HIGH}		2.6	—	50[4]	µs

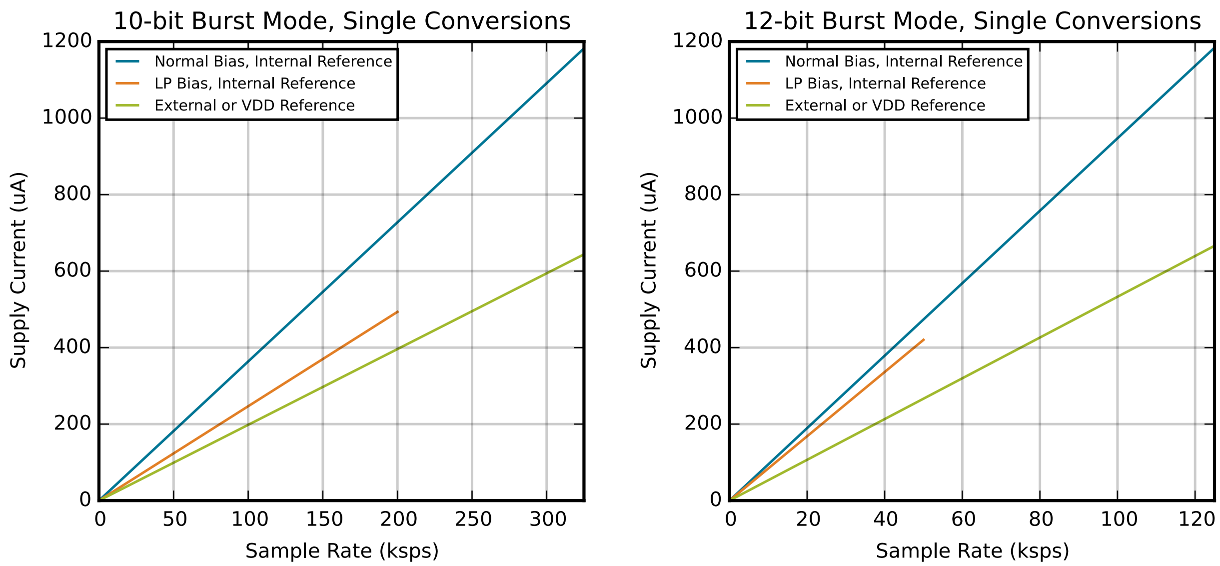


Figure 4.4. Typical ADC0 and Internal Reference Supply Current in Burst Mode

6. Pin Definitions

6.1 EFM8BB1x-QSOP24 Pin Definitions

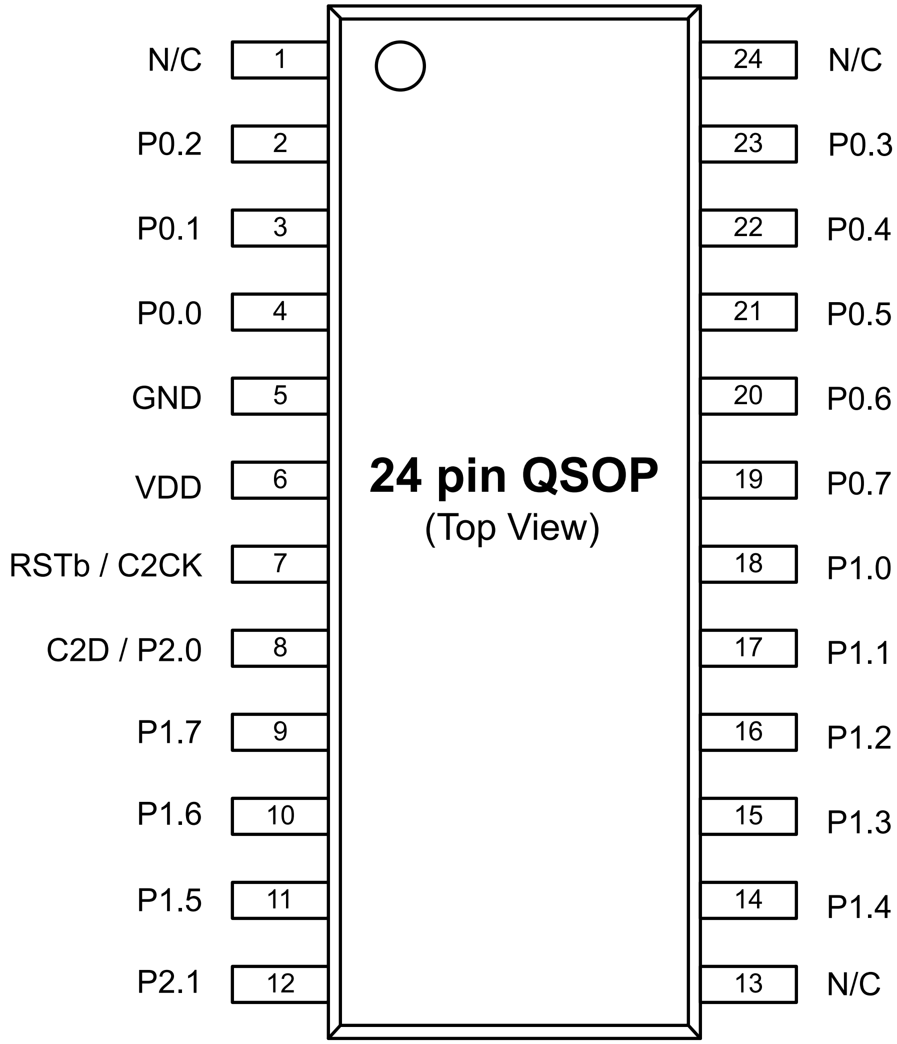


Figure 6.1. EFM8BB1x-QSOP24 Pinout

Table 6.1. Pin Definitions for EFM8BB1x-QSOP24

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	N/C	No Connection			
2	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.2 CMP0N.2

6.3 EFM8BB1x-SOIC16 Pin Definitions

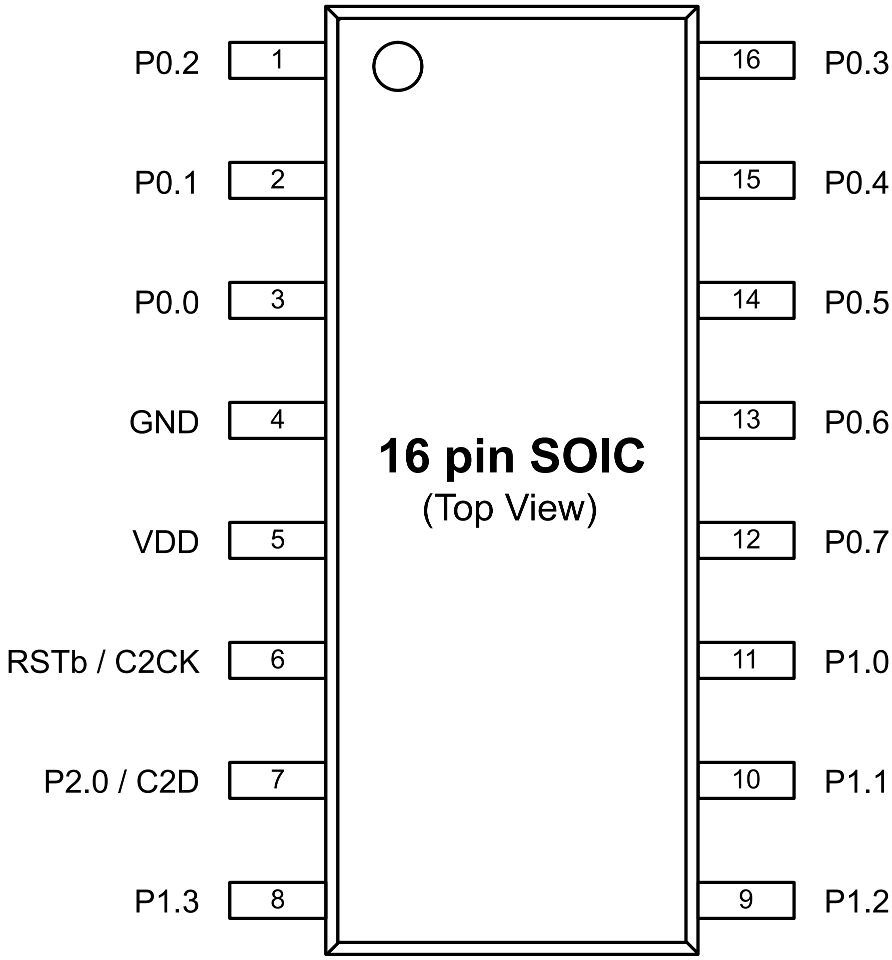


Figure 6.3. EFM8BB1x-SOIC16 Pinout

Table 6.3. Pin Definitions for EFM8BB1x-SOIC16

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
1	P0.2	Multifunction I/O	Yes	P0MAT.2 INT0.2 INT1.2	ADC0.2 CMP0P.2 CMP0N.2
2	P0.1	Multifunction I/O	Yes	P0MAT.1 INT0.1 INT1.1	ADC0.1 CMP0P.1 CMP0N.1
3	P0.0	Multifunction I/O	Yes	P0MAT.0 INT0.0 INT1.0	ADC0.0 CMP0P.0 CMP0N.0

7.3 QSOP24 Package Marking

Figure 7.3. QSOP24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

Dimension	Min	Max

Note:
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing is per the ANSI Y14.5M-1994 specification.
3. This Land Pattern Design is based on the IPC-7351 guidelines.
4. All metal pads are to be non-solder mask defined (NSMD). Clearance between the solder mask and the metal pad is to be 60 µm minimum, all the way around the pad.
5. A stainless steel, laser-cut and electro-polished stencil with trapezoidal walls should be used to assure good solder paste release.
6. The stencil thickness should be 0.125 mm (5 mils).
7. The ratio of stencil aperture to land pad size should be 1:1 for the perimeter pads.
8. A 2 x 2 array of 0.75 mm openings on a 0.95 mm pitch should be used for the center pad to assure proper paste volume.
9. A No-Clean, Type-3 solder paste is recommended.
10. The recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

8.3 QFN20 Package Marking

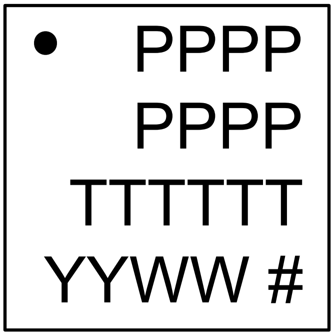


Figure 8.3. QFN20 Package Marking

The package marking consists of:
- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).

9. SOIC16 Package Specifications

9.1 SOIC16 Package Dimensions

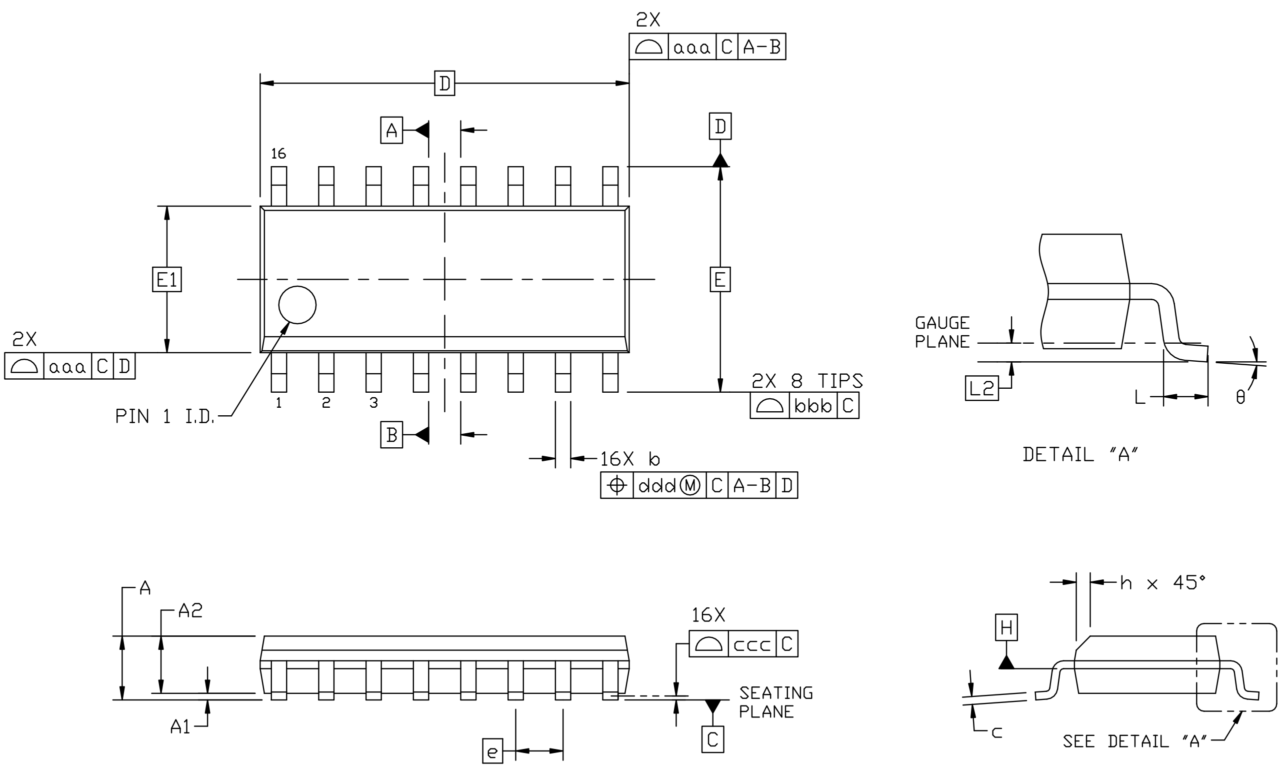


Figure 9.1. SOIC16 Package Drawing

Table 9.1. SOIC16 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.75
A1	0.10	—	0.25
A2	1.25	—	—
b	0.31	—	0.51
c	0.17	—	0.25
D	9.90 BSC		
E	6.00 BSC		
E1	3.90 BSC		
e	1.27 BSC		
L	0.40	—	1.27
L2	0.25 BSC		

9.2 SOIC16 PCB Land Pattern

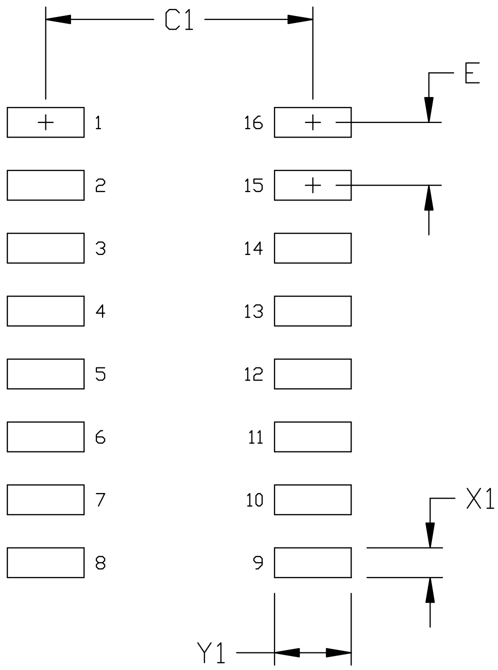


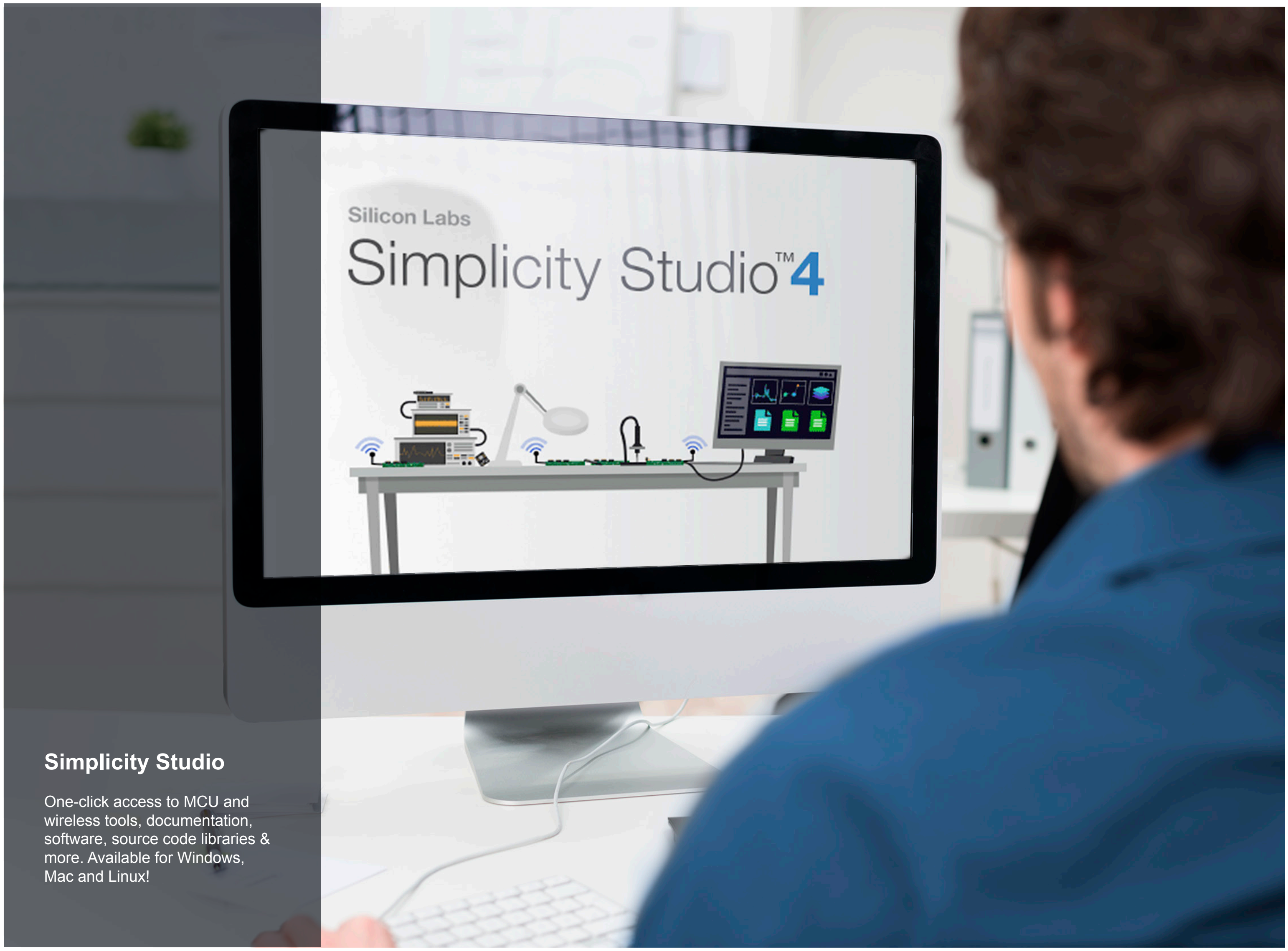
Figure 9.2. SOIC16 PCB Land Pattern Drawing

Table 9.2. SOIC16 PCB Land Pattern Dimensions

Dimension	Feature	(mm)
C1	Pad Column Spacing	5.40
E	Pad Row Pitch	1.27
X1	Pad Width	0.60
Y1	Pad Length	1.55

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. This Land Pattern Design is based on IPC-7351 pattern SOIC127P600X165-16N for Density Level B (Median Land Protrusion).
3. All feature sizes shown are at Maximum Material Condition (MMC) and a card fabrication tolerance of 0.05 mm is assumed.



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